

FDM2452NZ

Monolithic Common Drain N-Channel 2.5V Specified PowerTrench® MOSFET

General Description

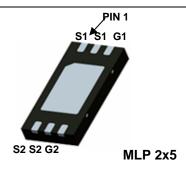
This dual N-Channel MOSFET has been designed using Fairchild Semiconductor's advanced Power Trench process to optimize the $R_{\text{DS}(\text{ON})}$ @ $V_{\text{GS}} = 2.5 \text{v}$ on special MicroFET lead frame with all the drains on one side of the package.

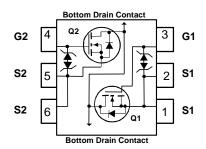
Applications

· Li-Ion Battery Pack

Features

- 8.1 A, 30 V $R_{DS(ON)} = 21 \ m\Omega \ @ \ V_{GS} = 4.5 \ V$ $R_{DS(ON)} = 25 \ m\Omega \ @ \ V_{GS} = 2.5 \ V$
- ESD protection Diode(note 3)
- Low Profile 0.8 mm maximum in the new package MicroFET 2 x 5 mm





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		30	V
V _{GSS}	Gate-Source Voltage		±12	V
I _D	Drain Current - Continuous	(Note 1a)	8.1	А
	– Pulsed		30	
P _D	Power Dissipation (Steady State)	(Note 1a)	2.2	W
		(Note 1b)	0.8	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

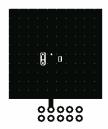
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	55	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		145	

Package Marking and Ordering Information

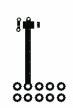
Device Marking	Device	Reel Size	Tape width	Quantity
2452Z	FDM2452NZ	13"	12mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics	l			1	
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$	30			V
ΔBV _{DSS} ΔΤ _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		24		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			1	μΑ
I_{GSS}	Gate-Body Leakage,	$V_{GS} = \pm 12 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ
On Chara	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	0.55	8.0	1.5	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25 $$ C		-3		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$\begin{array}{cccccccccccccccccccccccccccccccccccc$		13.6 13.9 14.6 15.7 19	21 21.5 23 25 31	mΩ
g FS	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_{D} = 8.1 \text{ A}$		46		S
Dvnamic	Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		980		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		160		pF
C _{rss}	Reverse Transfer Capacitance			110		pF
R _G	Gate Resistance	$V_{GS} = 0 V$, $f = 1.0 MHz$		1.8		Ω
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 15 \text{ V}, \qquad I_{D} = 1 \text{ A},$		9	18	ns
t _r	Turn-On Rise Time	$V_{GS} = 4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$		10	20	ns
t _{d(off)}	Turn-Off Delay Time			30	48	ns
t _f	Turn-Off Fall Time			8.7	17	ns
Q _g	Total Gate Charge	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 8.1 \text{ A},$		14	19	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 4.5 V		1.8		nC
Q_{gd}	Gate-Drain Charge			3.8		nC
Drain–Sou	urce Diode Characteristics					
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 1.8 \text{ A}$ (Note 2)		0.7	1.2	V
t _{rr}	Diode Reverse Recovery Time	I _F = 8.1 A,		15		nS
Q _{rr}	Diode Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$		4		nC

Notes:
1. R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



55°C/W when mounted on a 1in² pad of 2 oz copper



- b) 145°C/W when mounted on a minimum pad of 2 oz copper Scale 1 : 1 on letter size paper
- 2. Pulse Test: Pulse Width < $300\mu s$, Duty Cycle < 2.0%
- The diode connected between the gate and source serves only as protection againts ESD. No gate overvoltage rating is implied.

Typical Characteristics

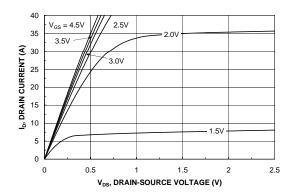


Figure 1. On-Region Characteristics.

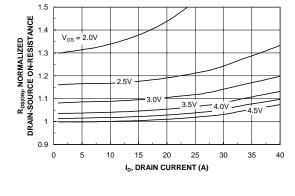


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

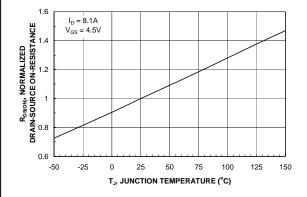


Figure 3. On-Resistance Variation with Temperature.

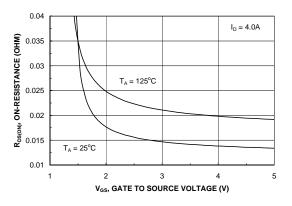


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

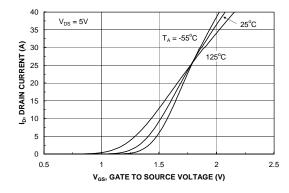


Figure 5. Transfer Characteristics.

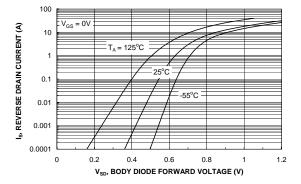
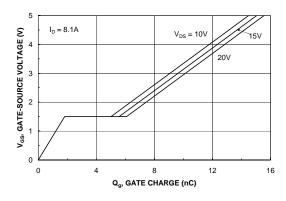


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



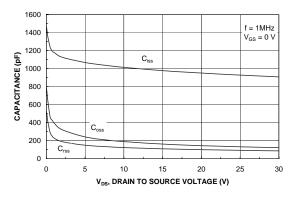
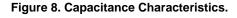
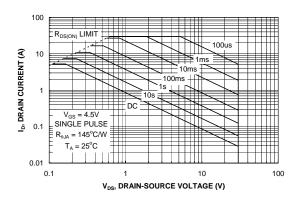


Figure 7. Gate Charge Characteristics.





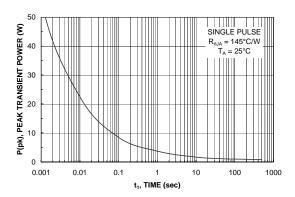


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

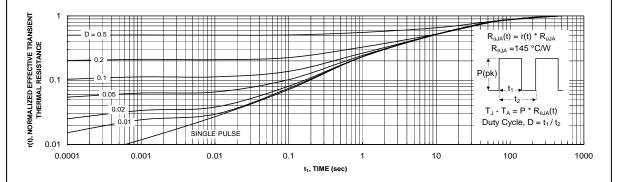
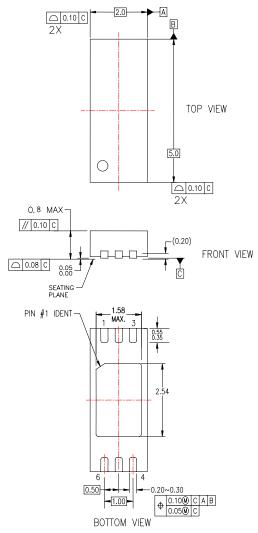
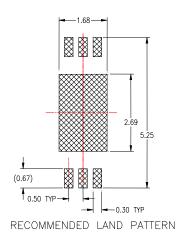


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

Dimensional Outline and Pad Layout





NOTES:

- A. NON-STANDARD JEDEC REGISTERED MOLDED PACKAGE OUTLINE.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994

MLP06XrevA

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Rev. I16